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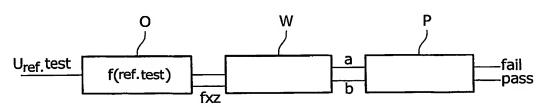
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(54) Title: METHOD AND CIRCUIT ARRANGEMENT FOR THE SELF-TESTING OF A REFERENCE VOLTAGE IN ELECTRONIC COMPONENTS



(57) Abstract: To provide a method for the self-testing of a reference voltage in electronic components, by means of which method there is specified a circuit arrangement for a self-test of the reference voltage that can be implemented in the form of an on-chip test, i.e. for which no external reference voltage source is required, provision is made for the reference voltage (U_{ref}) to be fed to a voltage-controlled oscillator whose output forms the input to a Wien-Robinson bridge whose output signal is checked in a phase detector for its phase shift relative to the input to the Wien-Robinson bridge to check the balance of the Wien-Robinson bridge, the Wien-Robinson bridge being set to be balanced at a frequency ($\Omega_{ref.test}$) that is generated in the oscillator at the nominal value ($U_{ref.test}$) selected for the reference voltage (U_{ref}), and a pass signal is generated if the bridge is balanced and a fail signal is generated if it is



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